PFI10N80A/PFB10N80A

750V N-Channel MOSFET

FEATURES

- Originative New Design
- 100% EAS Test
- Rugged Gate Oxide Technology
- Extremely Low Intrinsic Capacitances
- Remarkable Switching Characteristics
- Unequalled Gate Charge : 27.5 nC (Typ.)
- Extended Safe Operating Area
- Lower $R_{DS(ON)}$: 1.15 Ω (Typ.) @V_{GS}=10V

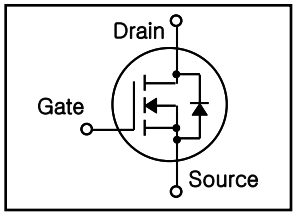
APPLICATION

- High current, High speed switching
- Suitable for power supplies, adaptors and PFC
- SMPS (Switched Mode Power Supplies)

BV_{DSS} = 750 V

$R_{DS(on)}$ = 1.15 Ω

I_D = 8.0 A



I2-PAK

1.Gate 2. Drain 3. Source

D2-PAK

1.Gate 2. Drain 3. Source

Absolute Maximum Ratings

T_C=25℃ unless otherwise specified

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	750	V
I_D	Drain Current – Continuous (T_C = 25℃)	8.0	A
	Drain Current – Continuous (T_C = 100℃)	5.1	A
I_{DM}	Drain Current – Pulsed (Note 1)	32	A
V_{GS}	Gate-Source Voltage	±30	V
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	700	mJ
I_{AR}	Avalanche Current (Note 1)	8.0	A
E_{AR}	Repetitive Avalanche Energy (Note 1)	17.9	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Power Dissipation (T_C = 25℃)	179	W
	– Derate above 25℃	1.43	W/℃
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	℃
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	℃

* Drain current limited by maximum junction temperature

Thermal Resistance Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.7	℃/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	--	0.5	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	

Electrical Characteristics T_C=25 °C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
On Characteristics						
V_{GS}	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 μA	2.5	--	4.5	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 4.0 A	--	1.15	1.30	Ω
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 μA	750	--	--	V
ΔBV_{DSS} /ΔT_J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to25℃	--	0.5	--	V/℃
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 750 V, V_{GS} = 0 V	--	--	10	μA
		V_{DS} = 600 V, T_C = 125℃	--	--	100	μA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 30 V, V_{DS} = 0 V	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V	--	--	-100	nA
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	--	1230	1600	pF
C_{oss}	Output Capacitance		--	135	176	pF
C_{rss}	Reverse Transfer Capacitance		--	10	13	pF
Switching Characteristics						
$t_{d(on)}$	Turn-On Time	V_{DS} = 375 V, I_D = 8.0 A, R_G = 25 Ω (Note 4,5)	--	24	48	ns
t_r	Turn-On Rise Time		--	15	30	ns
$t_{d(off)}$	Turn-Off Delay Time		--	80	160	ns
t_f	Turn-Off Fall Time		--	20	40	ns
Q_g	Total Gate Charge	V_{DS} = 600 V, I_D = 8.0 A, V_{GS} = 10 V (Note 4,5)	--	27.5	35	nC
Q_{gs}	Gate-Source Charge		--	7	--	nC
Q_{gd}	Gate-Drain Charge		--	10	--	nC
Source-Drain Diode Maximum Ratings and Characteristics						
I_S	Continuous Source-Drain Diode Forward Current		--	--	8.0	A
I_{SM}	Pulsed Source-Drain Diode Forward Current		--	--	32	
V_{SD}	Source-Drain Diode Forward Voltage	I_S = 8.0 A, V_{GS} = 0 V	--	--	1.5	V
trr	Reverse Recovery Time	I_S = 8.0 A, V_{GS} = 0 V di_F/dt = 100 A/μs (Note 4)	--	460	--	ns
Qrr	Reverse Recovery Charge		--	4.6	--	μC

Notes ;

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. I_{AS}=8.0A, V_{DD}=50V, R_G=25Ω, Starting T_J=25°C
3. I_{SD}≤8.0A, di/dt≤300A/μs, V_{DD}≤BV_{DSS} , Starting T_J=25 °C
4. Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%
5. Essentially Independent of Operating Temperature

Typical Characteristics

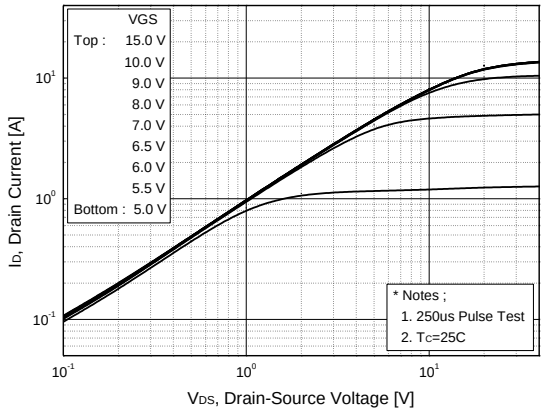


Figure 1. On Region Characteristics

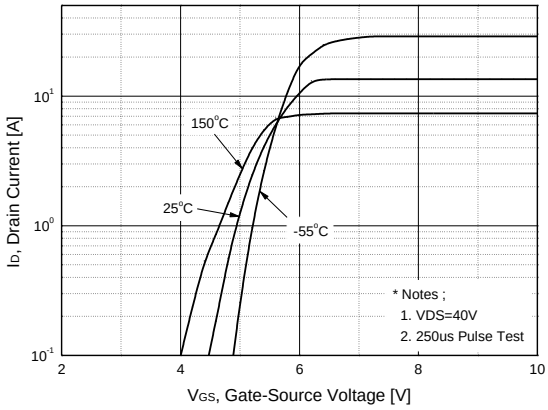


Figure 2. Transfer Characteristics

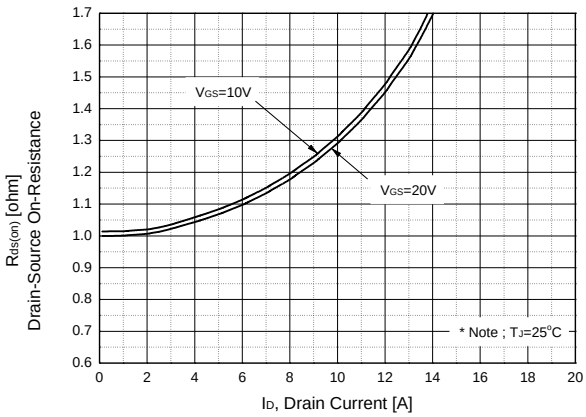


Figure 3. On Resistance Variation vs Drain Current and Gate Voltage

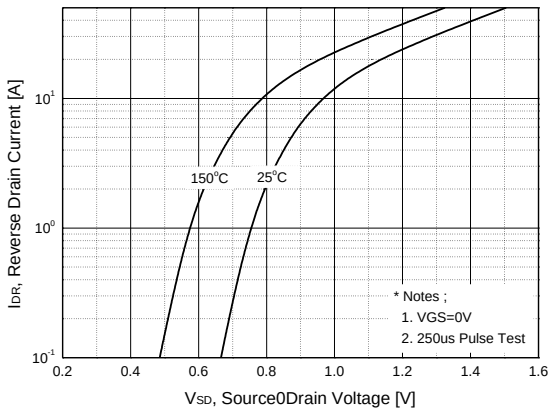


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

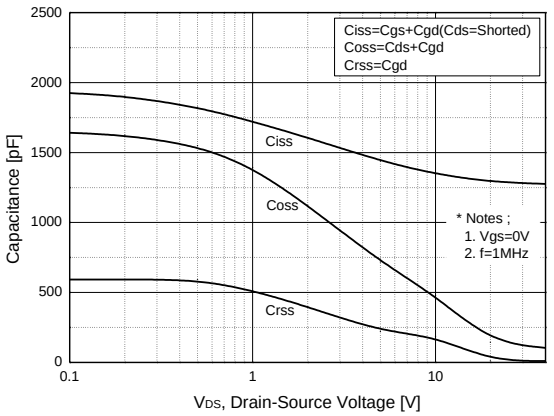


Figure 5. Capacitance Characteristics

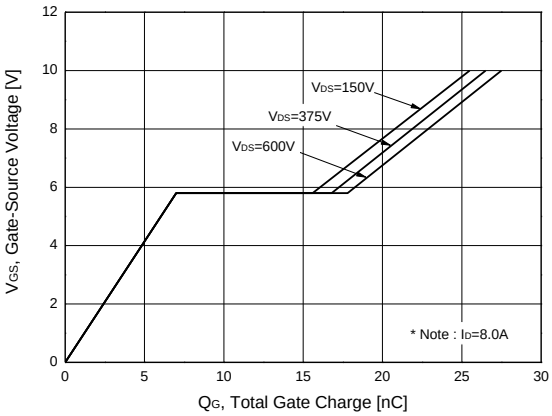


Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

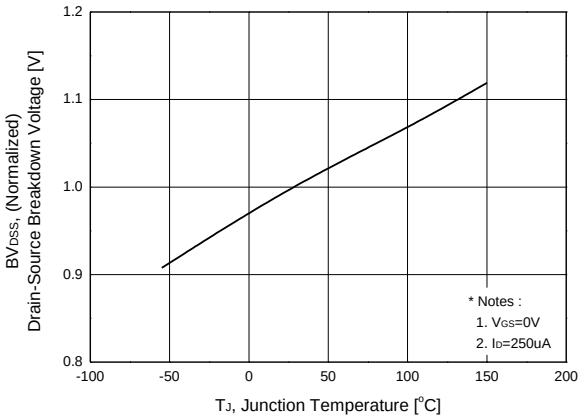


Figure 7. Breakdown Voltage Variation vs Temperature

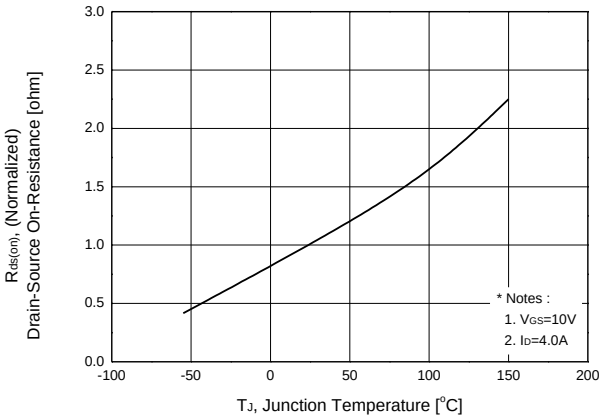


Figure 8. On-Resistance Variation vs Temperature

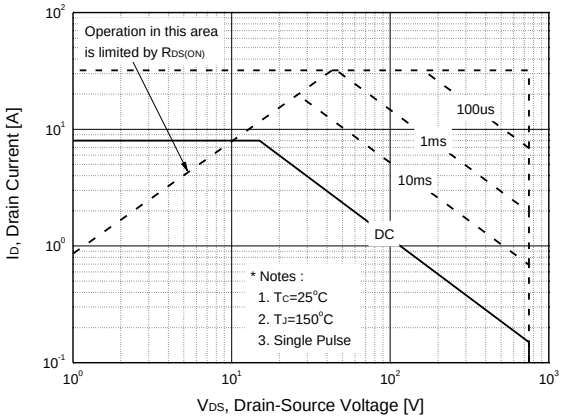


Figure 9. Maximum Safe Operating Area

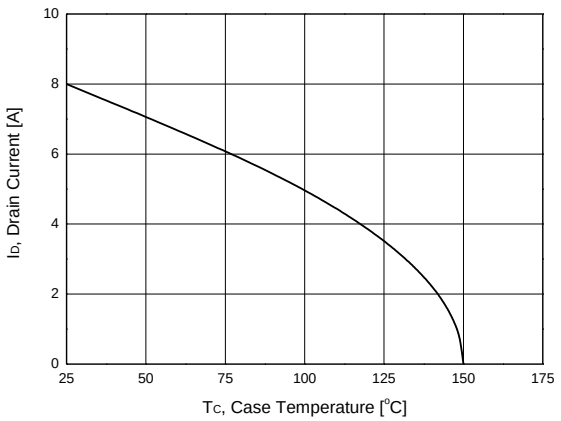


Figure 10. Maximum Drain Current vs Case Temperature

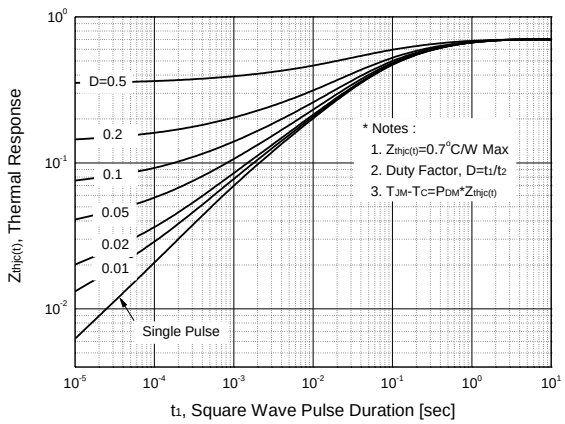


Figure 11. Transient Thermal Response Curve

Characteristics Test Circuit & Waveform

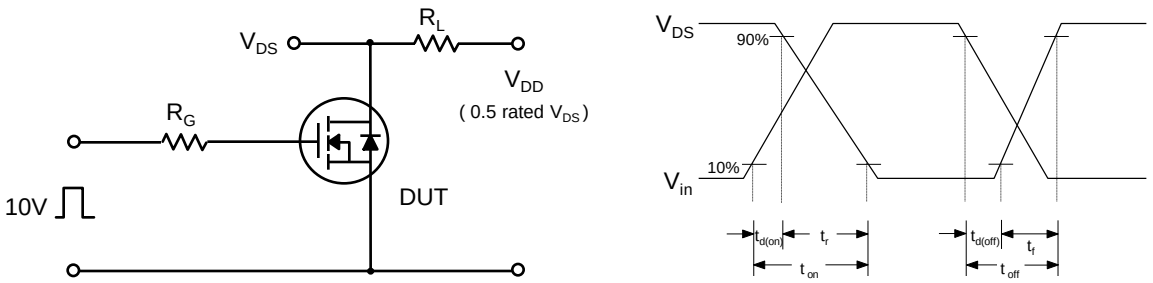


Fig 14. Resistive Switching Test Circuit & Waveforms

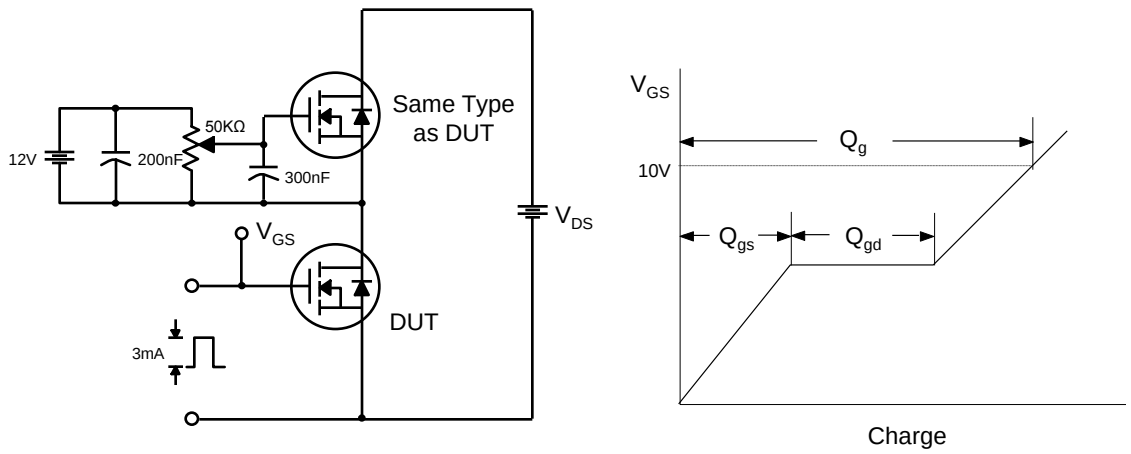


Fig 15. Gate Charge Test Circuit & Waveform

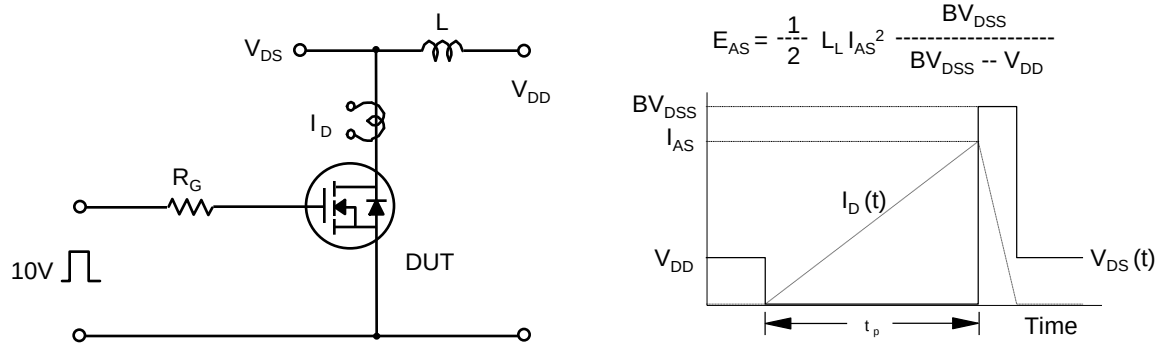
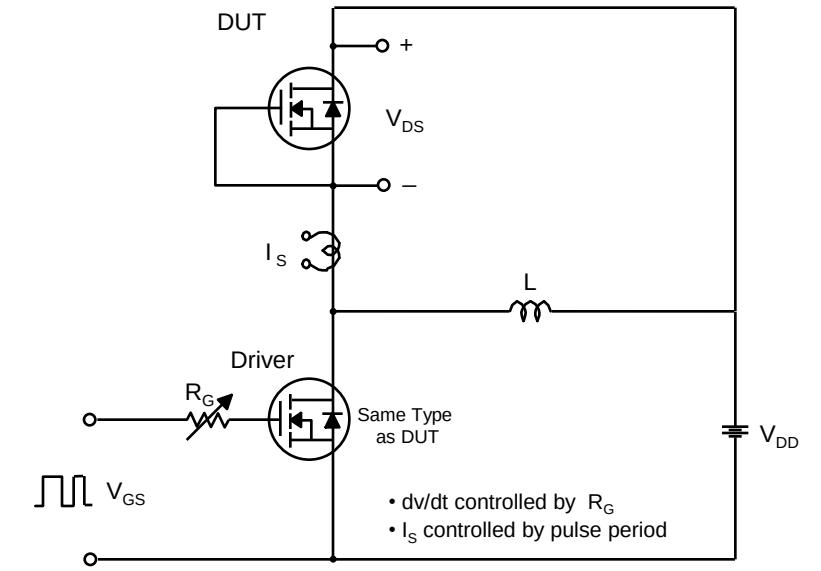


Fig 16. Unclamped Inductive Switching Test Circuit & Waveforms

Characteristics Test Circuit & Waveform (continued)



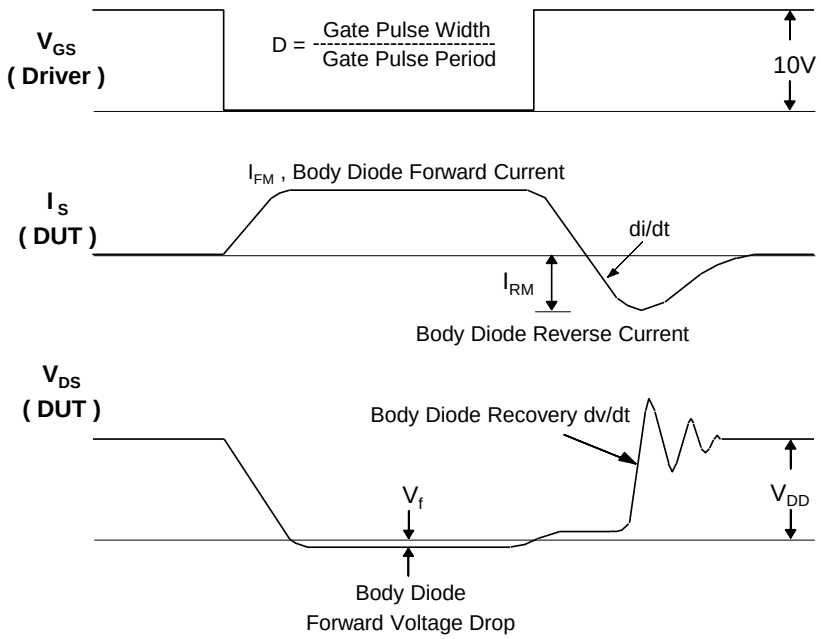
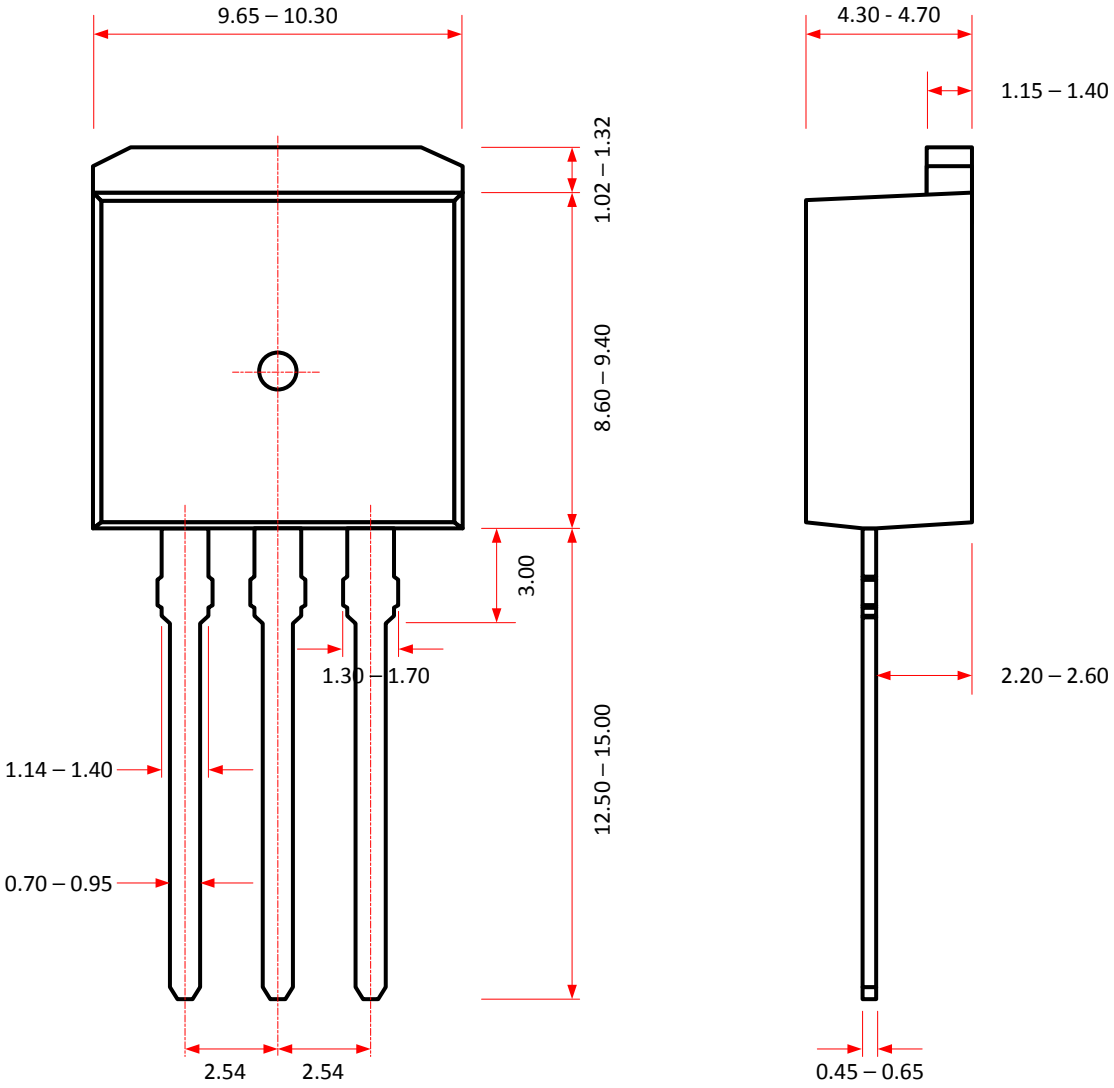


Fig 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Package Dimension

TO-262 (I2-PAK)



Package Dimension

TO-263 (D2-PAK)